Transistor Testers

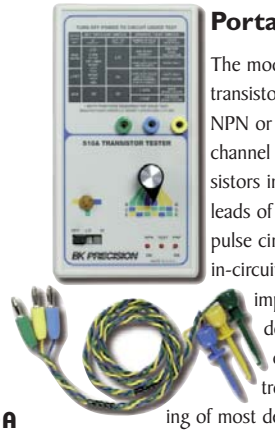
520C

Model 520C

Industrial Transistor Tester

The B+K Precision model 520C Transistor Tester is designed for in-circuit and out-of circuit transistor testing with special features for making additional tests on devices out-of circuit. The instrument is designed for a minimum amount of control manipulation, making for rapid testing of most devices.

- **Determines good or bad transistors, FET's, SCR's, or diodes.**
- **Patented limited-energy pulse circuit permits in-circuit testing in the presence of low shunt impedance's with complete safety for the device under test.**
- **Easy to operate panel eliminates the need to refer to a reference or operating manual-only three switches, no panel adjustments.**
- **Six position test switch makes it unnecessary to know the device terminal identification.**
- **A LED array identifies leakage in both Silicon and Germanium devices.**
- **Front Panel socket for out-of –circuit transistor testing.**



510A

Model 510A

Portable Transistor Tester

The model 510A performs Good/Bad test for transistors, FET's, and SCR's. It also identifies NPN or PNP for transistors, N-channel or P-channel for FET, FET-gate lead, all leads of transistors in LO drive, base lead in HI drive, and all leads of SCR. It uses a patented limited-energy pulse circuit, which provides highly successful in-circuit testing in the presence of low shunt impedance's with complete safety for the device under test. The instrument is designed for a minimum amount of control manipulation, allowing for rapid testing of most devices.

- **Rapid In-circuit and out-of circuit testing**
- **Good/Bad test**
- **NPN or PNP identification for transistors**
- **N-channel or P-channel identification for FET**
- **FET-gate and SCR lead identification**
- **Battery operated (4 x 1.5 AA batteries)**

Specifications

	520C	models 510A
IN-CIRCUIT TEST		
GOOD/BAD TEST	PNP and NPN transistors FET's, SCR's	
IDENTIFIES	NPN or PNP FET as N-channel or P-channel Silicone or germanium transistors transistors in LO drive, base lead in HI drive all leads of SCR	NPN or PNP FET as N-channel or P-channel FET-gate lead, all leads of
OUT-OF-CIRCUIT TEST		
GOOD/BAD TEST	PNP and NPN transistors FET's, SCR's	PNP and NPN transistors FET's
IDENTIFIES	NPN or PNP FET as N-channel or P-channel Silicone or germanium transistors	NPN or PNP FET as N-channel or P-channel
MEASURES	Reverse leakage from 0.1mA to 9mA	Does not apply
AUTOMATIC INDICATORS		
AUDIBLE TONE	GOOD	Does not apply
LED	NPN or PNP, Ge or Si	NPN or PNP, Ge or Si
TEST SWITCH	Base or Gate for good transistor or FET's	Base or Gate for good transistor or FET's
METER SCALES	Readable from 0.1μA to 9mA for Ice leakage, calibrated for silicon and germanium power and signal transistor leakage limits	Does not apply
APPLIED TEST CURRENTS		
BASE DRIVE*	250mA (HI), 1mA (LO)	
COLLECTOR*	125mA	
TEST REPETITION	10Hz	5Hz
IN-CIRCUIT SHUNT LIMIT FOR VALID GOOD/BAD TEST		
RESISTANCE	>10Ω (HI), 1.5kΩ (LO)	
CAPACITANCE	<15mF (HI), 0.3mF (LO)	<25mF (HI), 0.3μF (LO)
GENERAL		
POWER REQUIREMENT	9V Battery (Supplied) or optional AC adaptor	6VDC from 4 "AA" batteries (not supplied)
OPERATING TEMP	32° to 104°F (0° to 40°C), ≤75% RH	
DIMENSIONS (HxWxD)	7.5 x 4.0 x 2.0" (191 x 102 x 51 mm)	
WEIGHT	1 lb. (450g)	

Accessories

One Year Warranty

SUPPLIED: FP-6 Semiconductor Test Leads (three test leads w/mini-lock clips), Instruction manual, Battery (520C only)
Optional: BE 12 AC adaptor(9VDC)

* Duty Cycle @8% for 520C, 2% for 510A